

BACK-END

MOS-FET

IGBT

SWITCHING TIME & QG TEST SYSTEM スイッチングタイム&ゲート容量テストシステム

SWQR550 500V 50A

- SWQR550 has both function of resistive load switching time and gate capacity (QG) measurement. However, it can not measure resistive load switching time and gate capacity consecutively because each measurement characteristic is respected.
- SWQR550はR負荷スイッチングタイム測定のほか、ゲート容量(QG)測定機能を併せ持っています。ただし、各測定の特性を重視しているため、R負荷スイッチングとゲート容量の連続測定は行えません。

MODEL	SWQR550
SETTING RANGE(R-SWITCHING)	
MEASURABLE DEVICES	N/P MOS-FET, N/P IGBT
TEST ITEMS	td/td(on), tr, tstg/td(off), tf, Eon, Eoff
MEASUREMENT RANGE	0.1ns~10μs
VDD	1V~500V 1V STEP
ID(Limit)	0.1A~50.0A 0.1A STEP
Vgf	0.0V~20.0V 0.1V STEP
VGr	[Maximum pulse current 1A] [最大パルス電流1A] 0.0V~20.0V 0.1V STEP
ON TIME/OFF TIME	[Maximum pulse current 1A] [最大パルス電流1A] 1μs~100μs 1μs STEP
REPEAT	1~10
SETTING RANGE(QG)	
TEST ITEM	Vg-th, QGs, QGd, QG
MEASUREMENT RANGE	Vg-th : 00.0V~19.9V QGs/QGd: 000.00nC~199.99nC QG : 000.00nC~499.99nC
IC/ID	MAX 50A Measuring by VDD/Resistive load [VDD/R負荷により測定]
VCC/VDD	1V~500V 1V STEP
IG	0.01mA~9.99mA 0.01mA STEP
VG-CLAMP	1V~20V 1V STEP
BINNING	
OPEN/SHORT CHECK	VGF ON : VCE/VDS ≥ 1/2 VDD...OPEN VGF OFF : VCE/VDS ≤ 1/2 VDD...SHORT
BIN INDICATION	PASS, ERROR, LIMIT-FAIL, OPEN, SHORT
DIMENSIONS & WEIGHT	
MAIN UNIT	550(W)×860+400(D)×1700(H)··272kg



Measurement Waveform

